



AR

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

RECEIVED

DEC 11 2003

TC 1700

Applicant : BEVAN et al. Confirmation No: 2485  
Appl. No. : 09/486,715  
Filed : May 24, 2000  
Title : ANALYTICAL METHOD AND APPARATUS THEREFOR

TC/A.U. : 1743  
Examiner : Y. Gakh

Docket No.: : BEVA3004/REF  
Customer No: : 23364

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Assistant Commissioner for Patents  
Washington, D.C. 20231

Sir:

This Supplemental Information Disclosure Statement is being submitted in the above-identified patent application to correct an obvious error in the Country/Agency listed for reference EP 0 345 782 A in that WIPO was listed instead of EP. Also attached herewith is the Form PTO-1449 with the correct Country/Agency listed.

Accordingly, it is most respectfully requested that the Examiner acknowledge consideration of the information provided in this paper in accordance with prescribed procedures.

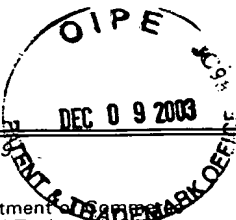
Respectfully submitted,  
BACON & THOMAS, PLLC

By: Richard E. Fichter  
Richard E. Fichter  
Registration No. 26,382

625 Slaters Lane, 4<sup>th</sup> Fl.  
Alexandria, Virginia 22314  
Phone: (703) 683-0500  
Facsimile: (703) 683-1080

REF:kdd  
SupplIDS.wpd

December 9, 2003



B/O Form PTO-1449

U.S. Department of Commerce  
Patent and Trademark Office

Information Disclosure Statement by Applicant

Atty. Docket Number

BEVA3004/REF

Serial Number

10/486,715

Applicant

BEVAN et al.

Filing Date

May 24, 2000

Group

1743

RECEIVED  
DEC 11 2003  
TC 1700

## U.S. Patent Documents

Examiner Initial	Document Number	Date	Patentee/Applicant	Class	Subclass	Filing Date if Appropriate

## Foreign Patent Documents

Examiner Initial	Document Number	Publication Date	Country/Agency	Class	Subclass	Translation	
						Yes	No
	0 345 782 A	12/13/89	EPO				

## Other Documents (Including Author, Title, Date, Pertinent Pages, Place of Publication, Etc.)


Examiner

Date Considered

EXAMINER: Initial if citation is considered, whether or not citation is in conformance with MPEP 609; Draw a line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.